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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In application of: Koç et al. Application No. 09/895,827

Filed: June 29, 2001

For: ELLIPTIC CURVE CRYPTOGRAPHIC

METHODS AND APPARATUS

Examiner: --

Date: December 26, 2001

Art Unit: 2131

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on December 26, 2001 as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231.

Attorney for Applicant

PURSUANT TO 37 C.F.R. § 1.97(b)(3)

COMMISSIONER FOR PATENTS WASHINGTON, DC 20231

Sir:

Listed on the accompanying form PTO-1449 and enclosed herewith are several English-language and/or non-English-language documents. Applicants respectfully request that these documents be listed as references cited on the issued patent.

The undersigned hereby certifies that the information submitted herewith was cited in an International Search Report in a counterpart PCT/EPC application on November 28, 2001, which was less than three months prior to the filing of this statement.

Respectfully submitted,

KLARQUIST SPARKMAN, LLP

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Mun W 2 Michael D. Jones

Registration No. 41,879

One World Trade Center, Suite 1600 121 S.W. Salmon Street Portland, Oregon 97204

Telephone: (503) 226-7391 Facsimile: (503) 228-9446

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INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

Docket: 245-59280 App: 09/895,827

Applicant: Koç et al.

Filed: June 29, 2001 Art Unit: 2131

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OTHER DOCUMENTS

il	OTHER DOCUMENTS
RADEMARK	Menezes, A., Handbook of Applied Cryptography, (CRC PRESS 1997), pp. 80-85.
	Koblitz, N., Algebraic Aspects of Cryptography, (Springer 1999), pp. 117-143.
	T. Okamoto et al., "An Efficient Digital Signature Scheme Based on an Elliptic Curve over the Ring Z_n ", in E.F. Brickel, Advances in Cryptology-Crypto 92, 2d ed., (Springer 1993), pp. 54-65.
	Koblitz, N., A Course in Number Theory and Cryptography, 2d ed., (Springer 1994) Second Edition, pp. 178-199.
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EXAMINER:

DATE

*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.

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